

Notice of References Cited	Application/Control No. 10/553,008		Applicant(s)/Patent Under Reexamination MATSUSHITA ET AL.	
	Examiner AMAR DAGLAWI		Art Unit 2618	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,291,193 A	03-1994	Isobe et al.	340/825.69
*	B	US-2002/0002582 A1	01-2002	Ewing et al.	709/202
*	C	US-2002/0037714 A1	03-2002	Takae et al.	455/419
*	D	US-2002/0040308 A1	04-2002	Hasegawa et al.	705/5
*	E	US-2002/0065070 A1	05-2002	Naiki, Takashi	455/419
*	F	US-2002/0082002 A1	06-2002	Fujii, Kenichi	455/419
*	G	US-2002/0119788 A1	08-2002	Parupudi et al.	455/456
*	H	US-6,470,085 B1	10-2002	Uranaka et al.	380/231
*	I	US-2002/0170975 A1	11-2002	Kawano et al.	235/492
*	J	US-2002/0177407 A1	11-2002	Mitsumoto, Hiroki	455/41
*	K	US-6,489,883 B1	12-2002	Iiyama et al.	340/5.1
*	L	US-2003/0045328 A1	03-2003	Natsuno, Takeshi	455/558
*	M	US-2003/0045333 A1	03-2003	Kimata et al.	455/574

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/553,008		Applicant(s)/Patent Under Reexamination MATSUSHITA ET AL.	
	Examiner AMAR DAGLAWI		Art Unit 2618	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0109218 A1	06-2003	Pourkeramati et al.	455/3.05
*	B	US-2003/0141989 A1	07-2003	Arisawa et al.	340/870.01
*	C	US-2003/0174839 A1	09-2003	Yamagata et al.	380/270
*	D	US-2003/0228892 A1	12-2003	Maalismaa et al.	455/575.7
*	E	US-6,687,350 B1	02-2004	Landry et al.	379/144.04
*	F	US-2004/0030761 A1	02-2004	Takeuchi et al.	709/220
*	G	US-2004/0058705 A1	03-2004	Morgan et al.	455/556.1
*	H	US-2004/0072592 A1	04-2004	Hasegawa, Yuka	455/558
*	I	US-6,729,550 B2	05-2004	Seita et al.	235/492
*	J	US-2004/0185830 A1	09-2004	Joao et al.	455/410
*	K	US-2004/0209650 A1	10-2004	Pearce, Graham N.	455/558
*	L	US-6,898,445 B2	05-2005	Slettengren et al.	455/567
*	M	US-6,973,327 B2	12-2005	Seita, Kazuhisa	455/550.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/553,008		Applicant(s)/Patent Under Reexamination MATSUSHITA ET AL.	
	Examiner AMAR DAGLAWI		Art Unit 2618	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,031,945 B1	04-2006	Donner, Irah H.	705/64
*	B	US-2006/0095454 A1	05-2006	Shankar et al.	707/101
*	C	US-2006/0234778 A1	10-2006	Matsushita et al.	455/565
*	D	US-7,231,202 B2	06-2007	Natsuno, Takeshi	455/410
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.